

Notice of References Cited

Application/Control No.

09/730,238

Applicant(s)/Patent Under

Reexamination

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Examiner

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Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,781,028 A	07-1998	Decuir, Joseph C.	326/30
	B	US-6,338,143 B1	01-2002	Shimazaki, Asao	713/340
	C	US-6,446,867 B1	09-2002	Sanchez, Jorge	235/454
	D	US-6,272,644 B1	08-2001	Urade et al.	713/320
	E	US-6,283,789 B1	09-2001	Tsai, Shui Chuan	439/502
	F	US-6,321,340 B1	11-2001	Shin et al.	713/310
	G	US-6,558,201 B1	05-2003	Begley et al.	439/638
	H	US-6,308,239 B1	10-2001	Osakada et al.	710/316
	I	US-6,577,337 B1	06-2003	Kang	348/207
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000231969 A	08-2000	Japan	YAGUCHI et al.	H01R 31/06
	O	JP 2000187537 A	07-2000	Japan	KOBAYASHI, KAZUO	G06F 03/00
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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